

Application Serial No.: 10/080,537
Amendment dated June 21, 2004
Reply to Notice of Allowance dated March 19, 2004

ABSTRACT

First, the wave-front aberration ~~in~~ of an optical system PL ~~subject to measurement~~ is measured using a measuring system 70 according to a usual method. After that, by using calculated correction information for aberration components of a second set of ~~order terms~~ orders based on a model for the measuring system 70 and aberration components of a first set of ~~order terms~~ orders measured before, the result of measuring aberration components of the second set of ~~order terms~~ orders is corrected. As a result, aberration components of the second set of ~~order terms~~ orders can be accurately obtained, so that the wave-front aberration ~~in~~ of the optical system ~~subject to measurement~~ is accurately obtained.